

Application/Con	trol No.	Applicant(s) Reexaminat	/Patent under ion	
10/565,251		KOBAYASH	II ET AL.	
Examiner		Art Unit		
VIJAY SHANKA	\R	2629		

SEARCHED					
Subclass	Date	Examiner			
85, 87-100,	10/24/2006	vs			
	Subclass 85,	Subclass Date			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST SEARCH	10/24/2006	VS		
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